FEI Quanta 3D FEG FIB Tool

- Resolution: 1.2 nm in the HiVac mode, 2.9 nm in LoVac mode, 7 nm with the FIB column.

- Detection Options: Everhart Thornley detector (EDT), continuous dynode multiplier (CDEM), ion-induced secondary electron (SE) imaging, backscattered electron detector (BSED), low-vacuum secondary electron detector (LVSED), gaseous analytical solid-state back scattered electron detector (ESEM GAD), high contrast detector (vCD), annular STEM detector (bright-field (BF), dark-field (DF), and high-angle annular dark field (HAADF) modes), Oxford Instruments Energy Dispersive Spectrometry (EDS)

- Gas injector modules (GIS) and Omniprobe micromanipulator can be used for TEM sample preparation and lift-out

- *In situ* study of the dynamic behavior of materials at different humidity (up to 100% RH) and temperatures (-10 °C to 1000 °C)